



## Features

- Wide bandgap SiC MOSFET technology
- Low On-Resistance with High Blocking Voltage
- Low Capacitances with High-Speed switching
- Low reverse recovery(Qrr)
- Halogen free, RoHS compliant

## Benefits

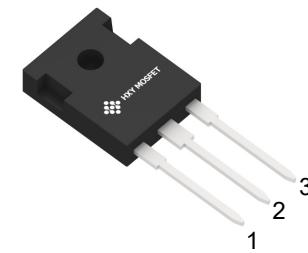
- Reduce switching losses
- Increased system Switching Frequency
- Increased power density
- Reduction of heat sink requirements

## Applications

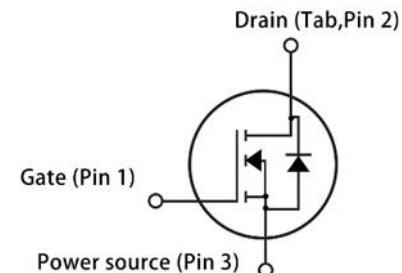
- Switch mode power supplies
- Renewable energy
- On Board Charger
- High Voltage DC/DC Converters



| Ordering Part Number | Package | Brand      |
|----------------------|---------|------------|
| NTHL082N65S3HF       | TO-247  | HXY MOSFET |



TO-247



## Maximum Ratings ( $T_c = 25^\circ\text{C}$ unless otherwise specified)

| Symbol        | Parameter                       | Test conditions                                      | Value   | Unit | Note    |
|---------------|---------------------------------|--|---------|------|---------|
| $V_{DSmax}$   | Drain-Source Voltage            | $V_{GS} = 0\text{V}$ , $I_D = 100\mu\text{A}$        | 650     | V    |         |
| $V_{GS}$      | Gate-Source voltage (transient) | $t_p \leq 500\text{ns}$ , duty cycle $\leq 1\%$      | -8/+20  | V    |         |
| $V_{GSop}$    | Recommend Gate-Source Voltage   | Static   | -4/+18  | V    |         |
| $I_D$         | Continuous Drain current        | $V_{GS} = 18\text{V}$ , $T_c = 25^\circ\text{C}$     | 36      | A    | Fig. 14 |
|               |                                 | $V_{GS} = 18\text{V}$ , $T_c = 100^\circ\text{C}$    | 25      |      |         |
| $I_{D,pulse}$ | Pulsed Drain Current            | Pulse with $t_p$ limited by $T_{jmax}$               | 57      | A    |         |
| $P_D$         | Power Dissipation               | $T_c = 25^\circ\text{C}$ , $T_j = 175^\circ\text{C}$ | 127     | W    | Fig.16  |
| $T_j$         | Operating junction temperature  |  | -55~175 | °C   |         |
| $T_{stg}$     | Storage temperature             |  | -55~175 | °C   |         |



### Thermal Characteristics

| Symbol       | Parameter                                   | Value |      |      | Unit | Note    |
|--------------|---|-------|------|------|------|---------|
|              |   | Min.  | Typ. | Max. |      |         |
| $R_{th(jc)}$ | Thermal resistance from Junction to Case    |       | 1.18 |      | K/W  | Fig. 15 |
| $R_{th(ja)}$ | Thermal resistance from Junction to Ambient |       | 40   |      | K/W  |         |

### Electrical Characteristics (T<sub>c</sub> = 25°C unless otherwise specified)

#### Static Characteristics

| Symbol        | Parameter                        | Test conditions  | Value |      |      | Unit      | Note         |
|---------------|----------------------------------|--|-------|------|------|-----------|--------------|
|               |                                  |  | Min.  | Typ. | Max. |           |              |
| $V_{(BR)DSS}$ | Drain-Source Breakdown voltage   | $V_{GS} = 0V, I_D = 100\mu A$  | 650   |      |      | V         |              |
| $V_{GS(th)}$  | Gate Threshold voltage           | $V_{GS} = V_{DS}, I_D = 5mA$   |       | 2.3  |      | V         | Fig. 9       |
|               |                                  | $V_{GS} = V_{DS}, I_D = 5mA, T_j = 175^\circ C$  |       | 1.6  |      |           |              |
| $I_{GSS}$     | Gate-Source Leakage current      | $V_{GS} = 18V, V_{DS} = 0V$  |       |      | 250  | nA        |              |
| $I_{DSS}$     | Zero Gate Voltage Drain Current  | $V_{DS} = 650V, V_{GS} = 0V, T_j = 25^\circ C$   |       | 1    | 50   | $\mu A$   |              |
| $R_{DS(on)}$  | Drain-Source On-state Resistance | $V_{GS} = 15V, I_D = 15A$<br>$V_{GS} = 18V, I_D = 15A$                                       |       | 90   | 75   | $m\Omega$ | Fig. 3, 4, 5 |
|               |                                  | $V_{GS} = 15V, I_D = 15A, T_j = 175^\circ C$<br>$V_{GS} = 18V, I_D = 15A, T_j = 175^\circ C$ |       | 112  | 105  |           |              |
| $g_{fs}$      | Transconductance                 | $V_{DS} = 15V, I_D = 15A$  |       | 10   |      | S         | Fig. 6       |
|               |                                  | $V_{DS} = 15V, I_D = 15A, T_j = 175^\circ C$   |       | 9    |      |           |              |



### Gate Charge Characteristics

| Symbol          | Parameter             | Test conditions                                      | Value |      |      | Unit | Note    |
|-----------------|-----------------------|--|-------|------|------|------|---------|
|                 |                       |  | Min.  | Typ. | Max. |      |         |
| Q <sub>GS</sub> | Gate to Source Charge | $V_{DS} = 400V$<br>$I_D = 15A$<br>$V_{GS} = -4V/18V$ |       | 11.3 |      | nC   | Fig. 10 |
| Q <sub>GD</sub> | Gate to Drain Charge  |  |       | 10.4 |      |      |         |
| Q <sub>G</sub>  | Total Gate Charge     |  |       | 32   |      |      |         |

### AC Characteristics

| Symbol              | Parameter                    | Test conditions  | Value |      |      | Unit     | Note    |
|---------------------|------------------------------|--|-------|------|------|----------|---------|
|                     |                              |  | Min.  | Typ. | Max. |          |         |
| C <sub>iss</sub>    | Input Capacitance            | $V_{GS} = 0V, V_{DS} = 600V$<br>$f = 1 MHz$<br>$V_{AC} = 25mV$ |       | 721  |      | pF       | Fig. 13 |
| C <sub>oss</sub>    | Output Capacitance           |  |       | 60   |      | pF       |         |
| C <sub>rss</sub>    | Reverse Transfer Capacitance |  |       | 4.9  |      | pF       |         |
| R <sub>G(int)</sub> | Internal Gate Resistance     | f=1 MHz, V <sub>AC</sub> = 25mV                                |       | 3.8  |      | $\Omega$ |         |



### Reverse Diode Characteristics

| Symbol        | Parameter                        | Test conditions  | Value |      |      | Unit | Note     |
|---------------|----------------------------------|--|-------|------|------|------|----------|
|               |                                  |  | Min.  | Typ. | Max. |      |          |
| $V_{SD}$      | Diode Forward Voltage            | $V_{GS} = -4V, I_{SD} = 7.5A$                                      |       | 4.4  |      | V    | Fig. 7,8 |
|               |                                  | $V_{GS} = -4V, I_{SD} = 7.5A, T_j = 175^\circ C$                   |       | 3.8  |      |      |          |
| $I_S$         | Continuous Diode Forward Current | $V_{GS} = -4V, T_C = 25^\circ C$                                   |       | 26   |      | A    |          |
| $I_{S,pulse}$ | Diode pulse Current              | $V_{GS} = -4V$ , pulse width $t_p$ limited by $T_{jmax}$           |       | 57   |      | A    |          |
| $t_{rr}$      | Reverse Recovery Time            | $V_{GS} = -4V, I_{SD} = 15A, V_R = 400V$<br>$dif/dt = 1000A/\mu s$ |       | 17   |      | nS   |          |
| $Q_{rr}$      | Reverse Recovery Charge          |  |       | 64   |      | nC   |          |
| $I_{rm}$      | Peak Reverse Recovery Current    |  |       | 4.9  |      | A    |          |

### Switching Characteristics

| Symbol       | Parameter              | Test conditions   | Value |      |      | Unit    | Note   |
|--------------|------------------------|---|-------|------|------|---------|--------|
|              |                        |   | Min.  | Typ. | Max. |         |        |
| $t_{d(on)}$  | Turn-On Delay Time     | $V_{DS} = 400V, V_{GS} = -4/+18V$<br>$I_D = 15 A, R_{G(ext)} = 5\Omega$<br>$L = 200\mu H$ |       | 2    |      | nS      | Fig.21 |
| $t_r$        | Rise Time              |   |       | 14   |      | nS      |        |
| $t_{d(off)}$ | Turn-Off Delay Time    |   |       | 11   |      | nS      |        |
| $t_f$        | Fall Time              |   |       | 3.5  |      | nS      |        |
| $E_{on}$     | Turn-On Energy         |   |       | 44   |      | $\mu J$ | Fig.19 |
| $E_{off}$    | Turn-Off Energy        |   |       | 16   |      | $\mu J$ |        |
| $E_{tot}$    | Total switching energy |   |       | 60   |      | $\mu J$ |        |



## Typical Performance

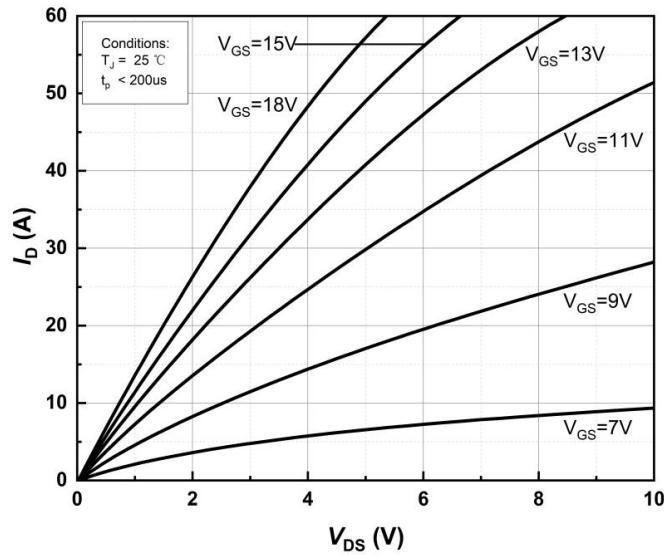


Figure 1. Output characteristics at  $T_j=25^\circ\text{C}$

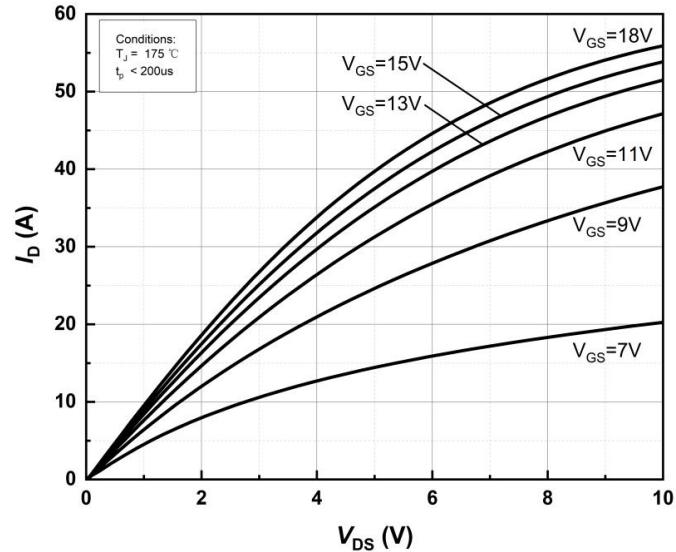


Figure 2. Output characteristics at  $T_j=175^\circ\text{C}$

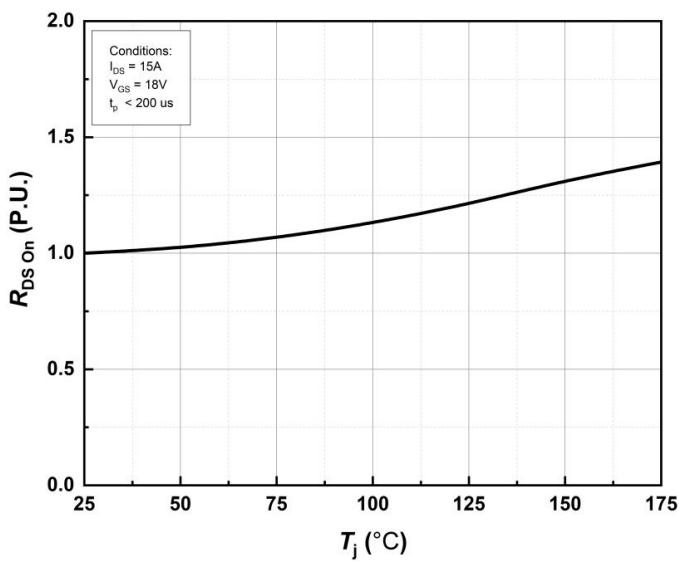


Figure 3. Normalized On-Resistance vs. Temperature

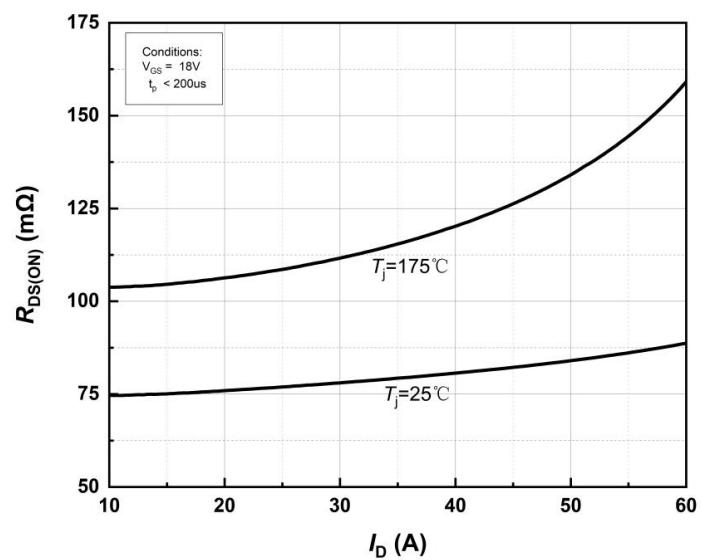


Figure 4. On-Resistance vs. Drain current for Various Temperature

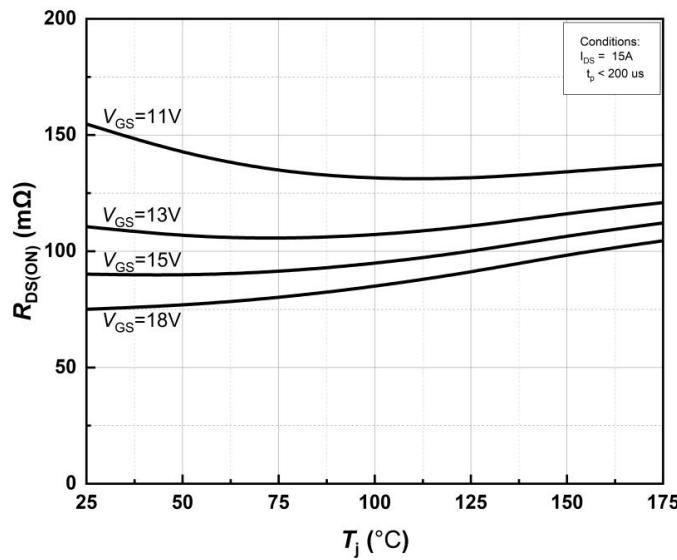


Figure 5. On-Resistance vs. Temperature for Various Gate Voltage

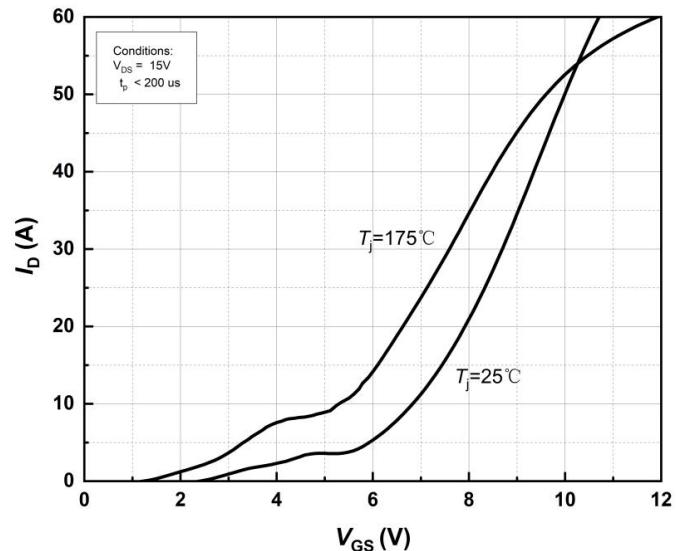


Figure 6. Transfer Characteristics for Various Junction Temperatures

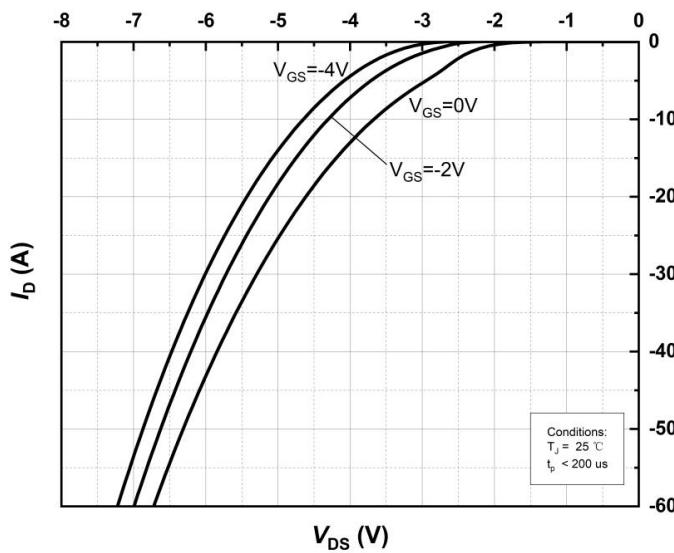


Figure 7. Body Diode Characteristics at  $T_j=25^\circ\text{C}$

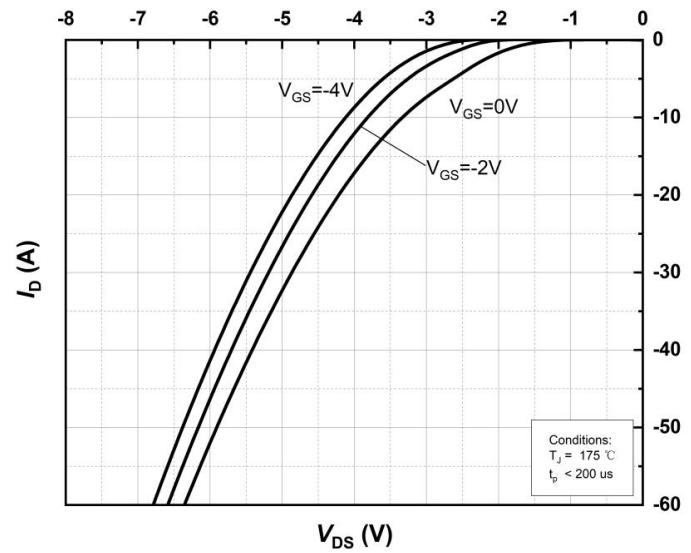


Figure 8. Body Diode Characteristics at  $T_j=175^\circ\text{C}$

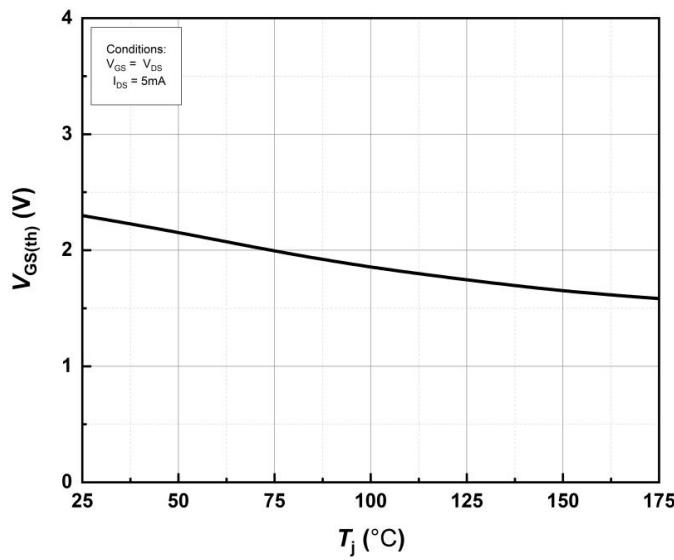


Figure 9. Threshold Voltage vs. Temperature

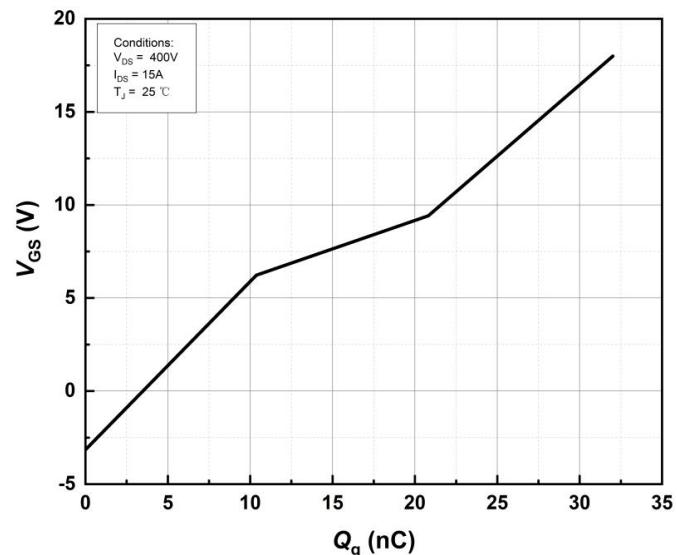


Figure 10 Gate Charge Characteristics

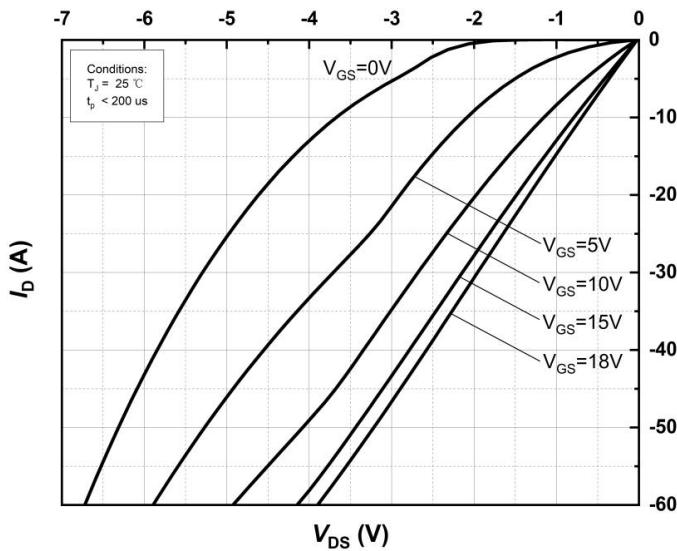


Figure 11. 3rd Quadrant Characteristic at  $T_j=25\text{°C}$

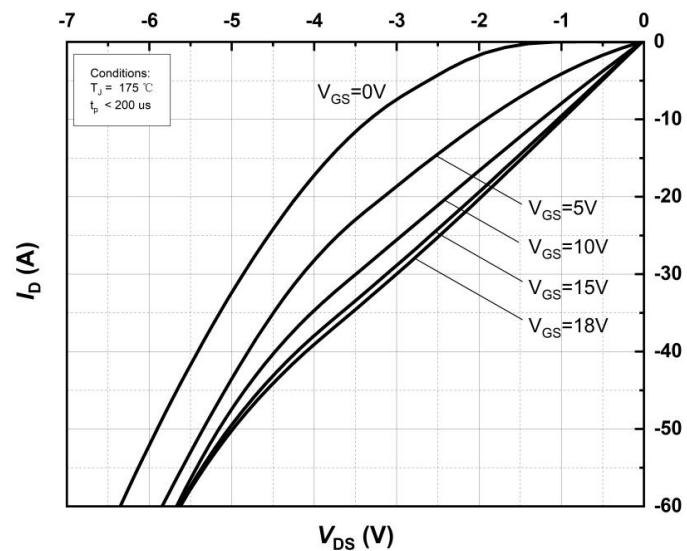


Figure 12. 3rd Quadrant Characteristic at  $T_j=175\text{°C}$

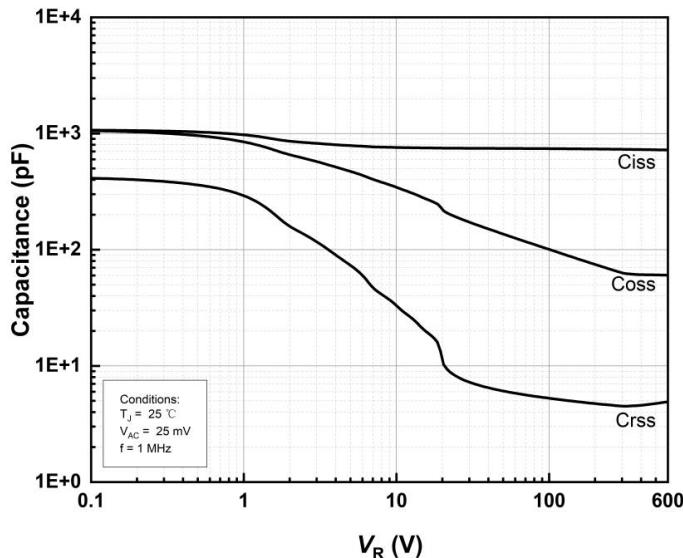


Figure 13. Capacitances vs. Drain-Source Voltage (0 – 600V)

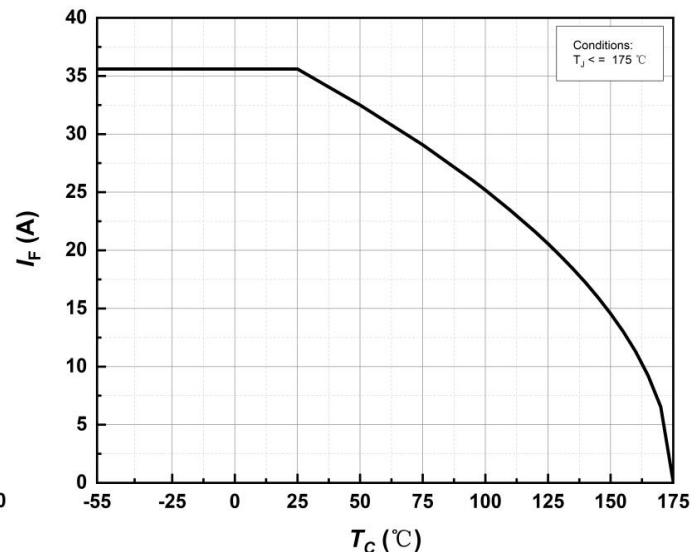


Figure 14. Continuous Drain Current Derating vs Case Temperature

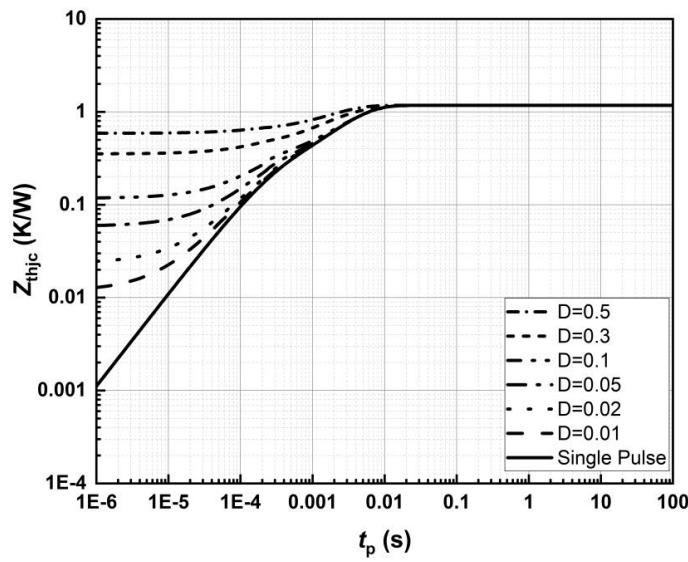


Figure 15. Transient Thermal Impedance (Junction – Case)

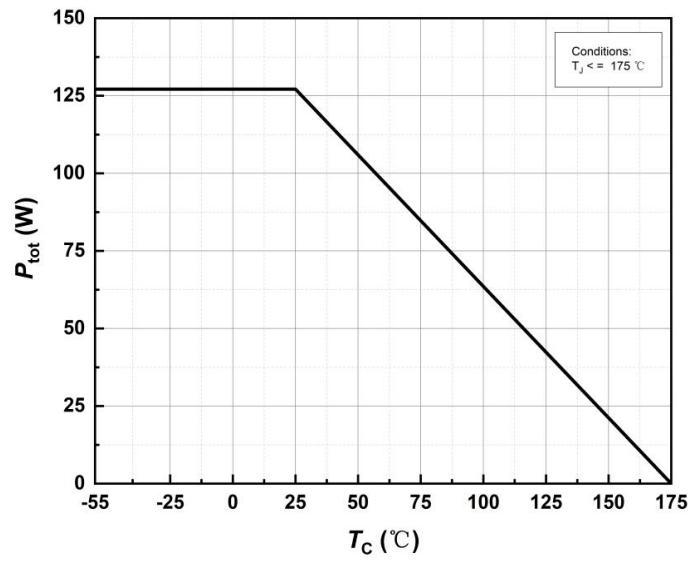


Figure 16. Maximum Power Dissipation Derating vs. Case Temperature

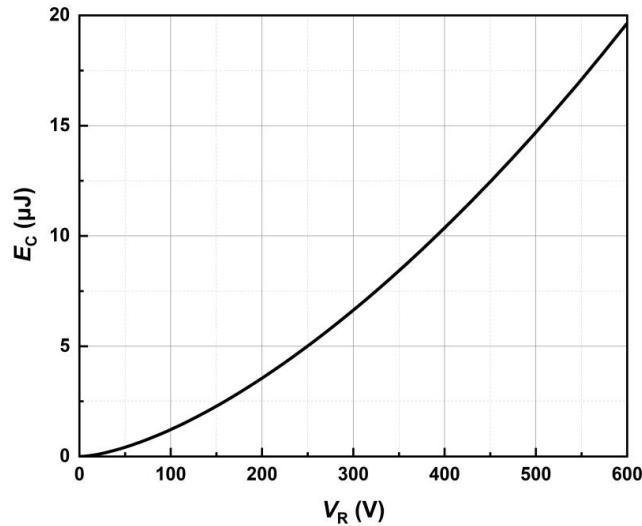
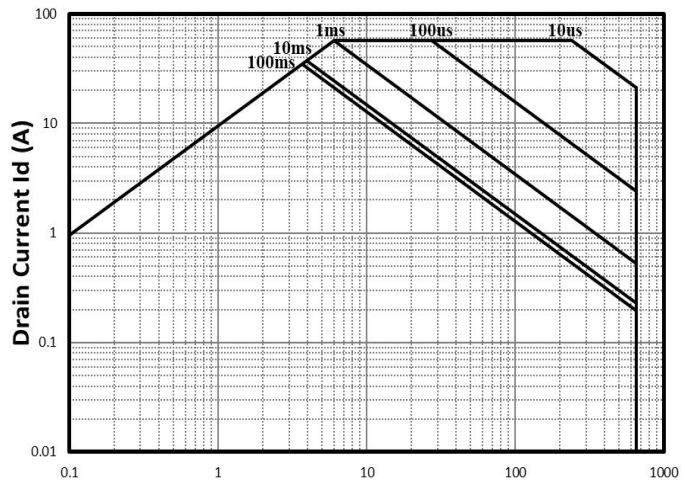


Figure 17. Output Capacitor Stored Energy



Drain-Source Voltage  $V_{DS}$  (V)

Figure 18. Safe Operating Area

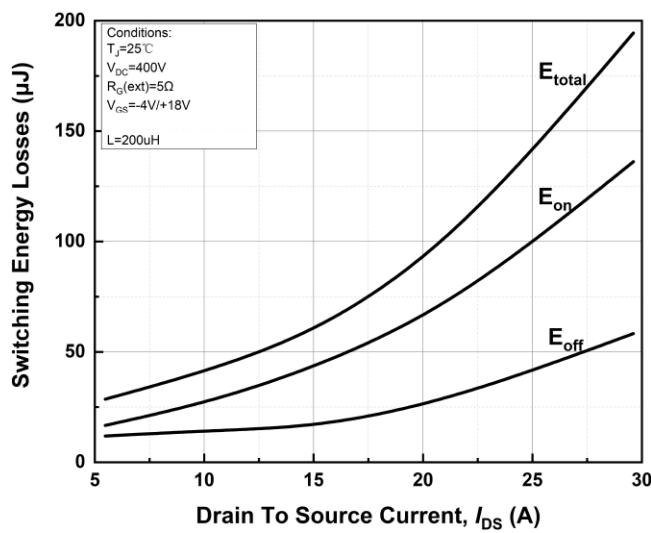


Figure 19. Clamped Inductive Switching Energy vs.  
Drain Current( $V_{DD} = 400\text{V}$ )

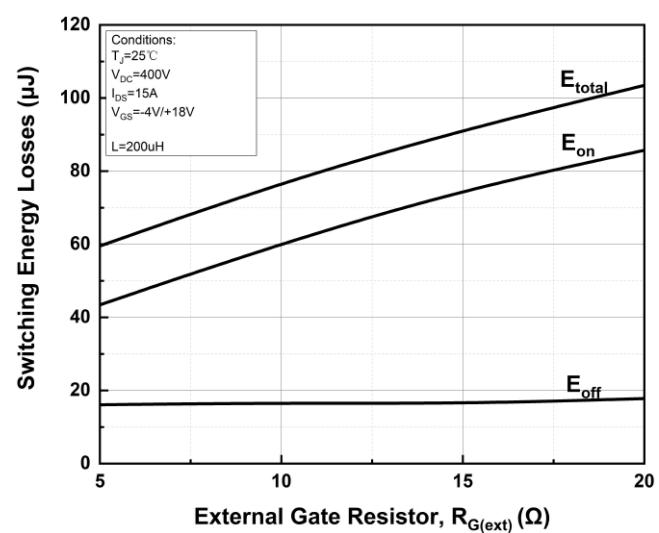


Figure 20. Clamped Inductive Switching  
Energy vs.  $R_{G(\text{ext})}$

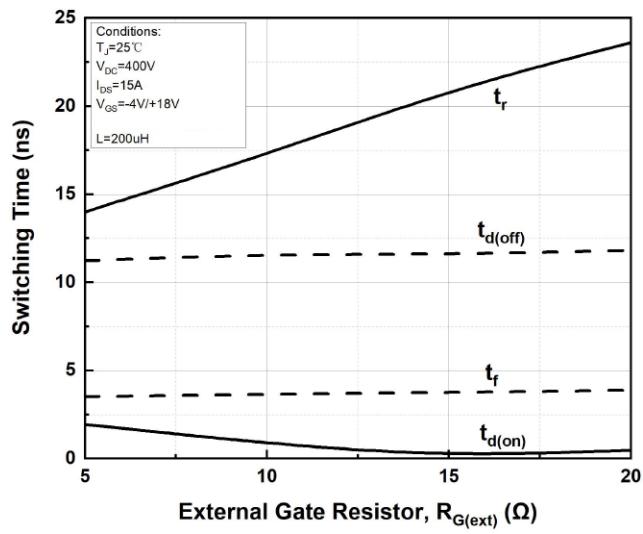
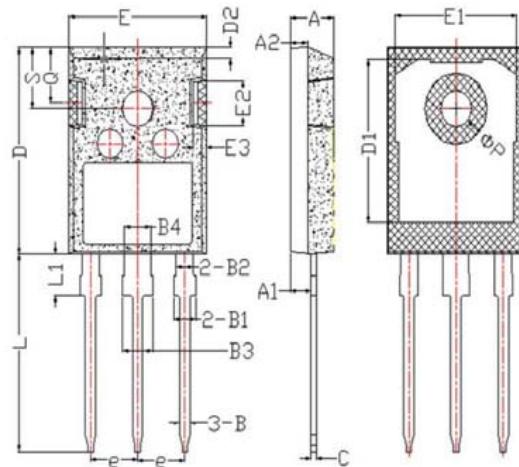


Figure 21. Switching Times vs.  $R_{\text{G(ext)}}$



## Package Dimensions

Package TO-247



| Items    | Values(mm) |      |
|----------|------------|------|
|          | MIN        | MAX  |
| A        | 4.6        | 5.2  |
| A1       | 2.2        | 2.6  |
| B        | 0.9        | 1.4  |
| B1       | 1.75       | 2.35 |
| B2       | 1.75       | 2.15 |
| B3       | 2.8        | 3.35 |
| B4       | 2.8        | 3.15 |
| C        | 0.5        | 0.7  |
| D        | 20.6       | 21.3 |
| D1       | 16         | 18   |
| E        | 15.5       | 16.1 |
| E1       | 13         | 14.7 |
| E2       | 3.8        | 5.3  |
| E3       | 0.8        | 2.6  |
| e        | 5.2        | 5.2  |
| L        | 19         | 20.5 |
| L1       | 3.9        | 4.6  |
| $\Phi_p$ | 3.3        | 3.7  |
| Q        | 5.2        | 6    |
| S        | 5.8        | 6.6  |



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